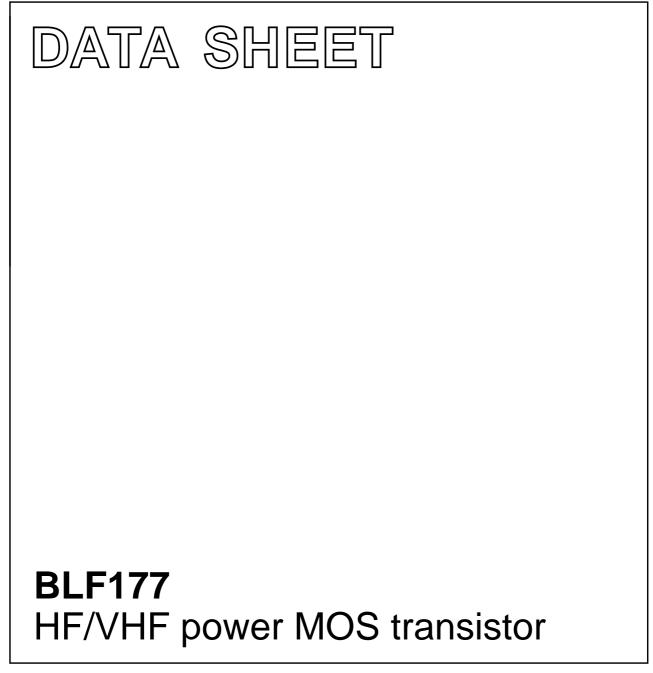
DISCRETE SEMICONDUCTORS



Product specification File under Discrete Semiconductors, SC08a September 1992



### **BLF177**

### FEATURES

- High power gain
- Low intermodulation distortion
- · Easy power control
- Good thermal stability
- Withstands full load mismatch.

#### DESCRIPTION

Silicon N-channel enhancement mode vertical D-MOS transistor designed for industrial and military applications in the HF/VHF frequency range.

The transistor is encapsulated in a 4-lead, SOT121 flange envelope, with a ceramic cap. All leads are isolated from the flange.

A marking code, showing gate-source voltage ( $V_{GS}$ ) information is provided for matched pair applications. Refer to the 'General' section for further information.

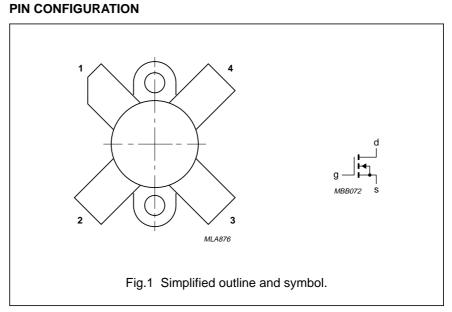
#### **PINNING - SOT121**

PIN	DESCRIPTION				
1	drain				
2	source				
3	gate				
4	source				

#### QUICK REFERENCE DATA

RF performance at  $T_h = 25$  °C in a common source test circuit.

MODE OF OPERATION	f (MHz)	V <sub>DS</sub> (V)	P <sub>L</sub> (W)	G <sub>P</sub> (dB)	η <sub>D</sub> (%)	d <sub>3</sub> (dB)	d <sub>5</sub> (dB)
SSB class-AB	28	50	150 (PEP)	> 20	> 35	< -30	< -30
CW class-B	108	50	150	typ. 19	typ. 70	_	_



### CAUTION

The device is supplied in an antistatic package. The gate-source input must be protected against static charge during transport and handling.

#### WARNING

Product and environmental	safety - toxic materials
i i oudot and on in onitional	

This product contains beryllium oxide. The product is entirely safe provided that the BeO disc is not damaged. All persons who handle, use or dispose of this product should be aware of its nature and of the necessary safety precautions. After use, dispose of as chemical or special waste according to the regulations applying at the location of the user. It must never be thrown out with the general or domestic waste.

### BLF177

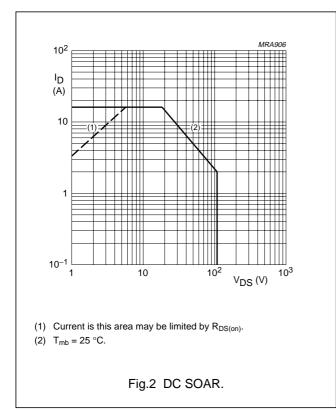
#### LIMITING VALUES

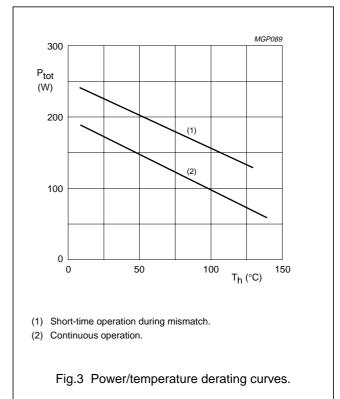
In accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>DS</sub>	drain-source voltage		_	110	V
±V <sub>GS</sub>	gate-source voltage		-	20	V
I <sub>D</sub>	DC drain current		-	16	A
P <sub>tot</sub>	total power dissipation	up to $T_{mb} = 25 \ ^{\circ}C$	-	220	W
T <sub>stg</sub>	storage temperature		-65	150	°C
Tj	junction temperature		_	200	°C

### THERMAL RESISTANCE

SYMBOL	PARAMETER	THERMAL RESISTANCE
R <sub>th j-mb</sub>	thermal resistance from junction to mounting base	max. 0.8 K/W
R <sub>th mb-h</sub>	thermal resistance from mounting base to heatsink	max. 0.2 K/W





### BLF177

#### CHARACTERISTICS

 $T_j = 25 \ ^{\circ}C$  unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$I_{D} = 50 \text{ mA}; V_{GS} = 0$	110	-	-	V
I <sub>DSS</sub>	drain-source leakage current	$V_{GS} = 0; V_{DS} = 50 V$	-	-	2.5	mA
I <sub>GSS</sub>	gate-source leakage current	$\pm V_{GS} = 20 \text{ V}; \text{ V}_{DS} = 0$	-	-	1	μA
V <sub>GS(th)</sub>	gate-source threshold voltage	I <sub>D</sub> = 50 mA; V <sub>DS</sub> = 10 V	2	-	4.5	V
$\Delta V_{GS}$	gate-source voltage difference of matched pairs	I <sub>D</sub> = 50 mA; V <sub>DS</sub> = 10 V	-	-	100	mV
<b>g</b> fs	forward transconductance	I <sub>D</sub> = 5 A; V <sub>DS</sub> = 10 V	4.5	6.2	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	I <sub>D</sub> = 5 A; V <sub>GS</sub> = 10 V	-	0.2	0.3	Ω
I <sub>DSX</sub>	on-state drain current	V <sub>GS</sub> = 10 V; V <sub>DS</sub> = 10 V	-	25	-	А
C <sub>is</sub>	input capacitance	$V_{GS} = 0; V_{DS} = 50 V; f = 1 MHz$	-	480	-	pF
C <sub>os</sub>	output capacitance	$V_{GS} = 0; V_{DS} = 50 V; f = 1 MHz$	-	190	-	pF
C <sub>rs</sub>	feedback capacitance	$V_{GS} = 0; V_{DS} = 50 V; f = 1 MHz$	-	14	-	pF

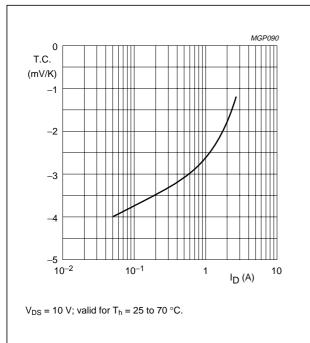
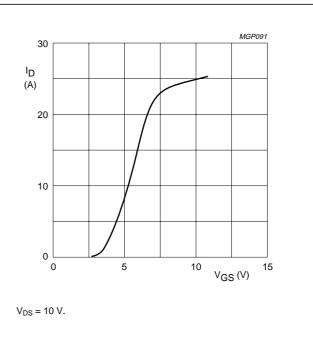
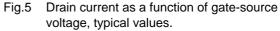
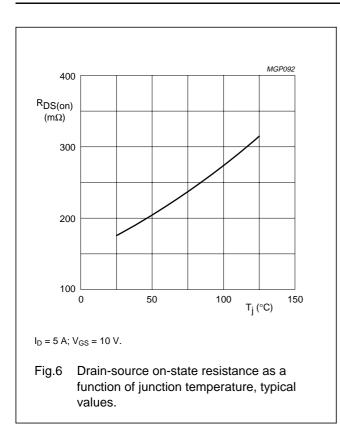


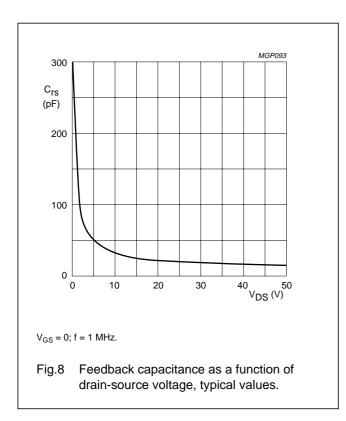
Fig.4 Temperature coefficient of gate-source voltage as a function of drain current, typical values.





# BLF177





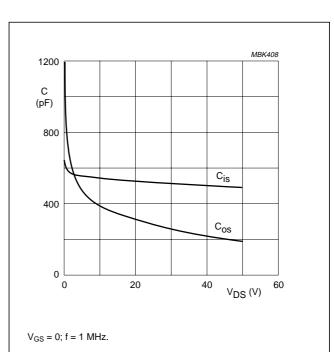


Fig.7 Input and output capacitance as functions of drain-source voltage, typical values.

**BLF177** 

200

### **APPLICATION INFORMATION FOR CLASS-AB OPERATION**

 $T_h = 25 \text{ °C}; R_{th mb-h} = 0.2 \text{ K/W}; Z_L = 6.25 + j0 \Omega$  unless otherwise specified. RF performance in SSB operation in a common source class-AB circuit. f<sub>1</sub> = 28.000 MHz; f<sub>2</sub> = 28.001 MHz.

MODE OF OPERATION	f (MHz)	V <sub>DS</sub> (V)	I <sub>DQ</sub> (A)	P <sub>L</sub> (W)	G <sub>P</sub> (dB)	η <sub>D</sub> (%)	d <sub>3</sub> (dB) (note 1)	d <sub>5</sub> (dB) (note 1)
SSB, class-AB	28	50	0.7	20 to 150 (PEP)	> 20 typ. 35	> 35 typ. 40	< -30 typ35	< -30 typ38

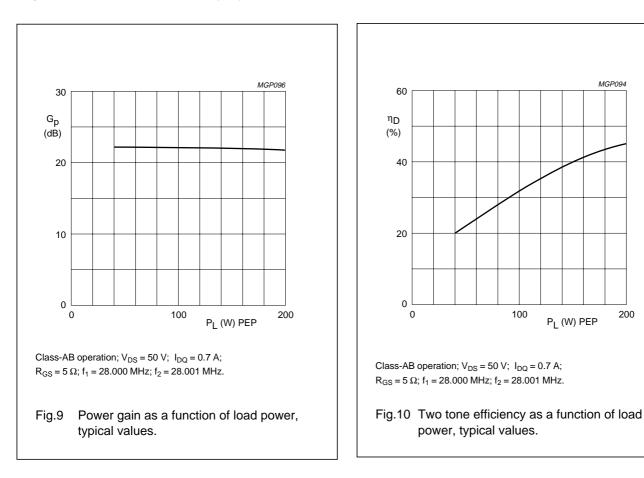
#### Note

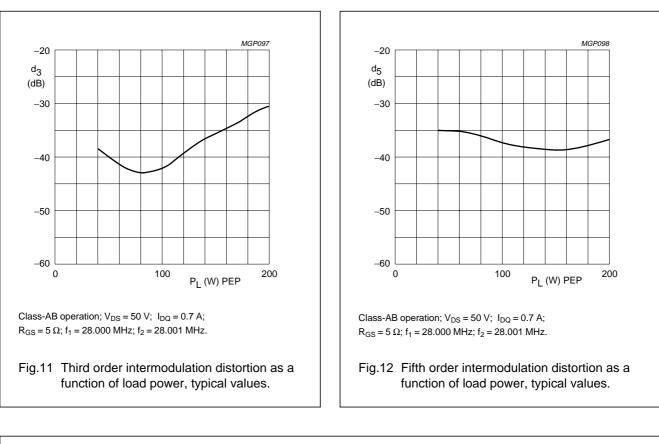
1. Stated figures are maximum values encountered at any driving level between the specified value of PEP and are referred to the according level of either the equal amplified tones. Related to the according peak envelope power these figures should be decreased by 6 dB.

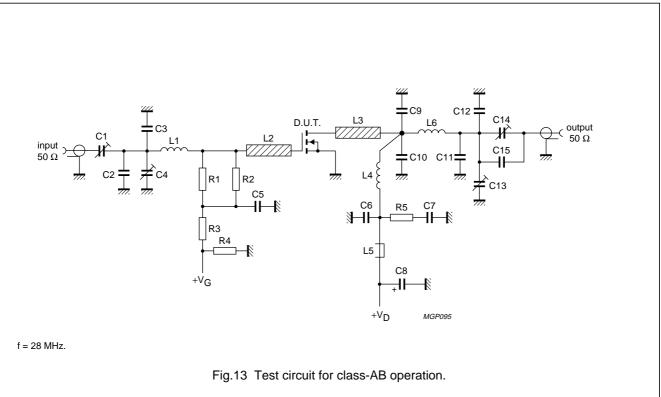
#### **Ruggedness in class-AB operation**

The BLF177 is capable of withstanding a load mismatch corresponding to VSWR = 50 through all phases under the following conditions:

 $V_{DS} = 50 \text{ V}; \text{ f} = 28 \text{ MHz}$  at rated output power.







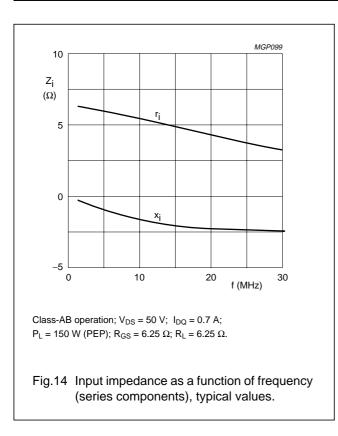
#### COMPONENT DESCRIPTION VALUE DIMENSIONS CATALOGUE NO. C1, C4, C13, C14 film dielectric trimmer 7 to 100 pF 2222 809 07015 C2 multilayer ceramic chip capacitor 56 pF (note 1) C3, C11 multilayer ceramic chip capacitor 62 pF (note 1) C5, C6 multilayer ceramic chip capacitor 100 nF 2222 852 47104 3×100 nF C7 multilayer ceramic chip capacitor 2222 852 47104 C5 multilayer ceramic chip capacitor 10 nF 2222 852 47103 C7 multilayer ceramic chip capacitor $3 \times 100 \text{ nF}$ 2222 852 47104 C8 electrolytic capacitor 2.2 µF, 63 V C9, C10 multilayer ceramic chip capacitor 20 pF (note 1) C12 multilayer ceramic chip capacitor 100 pF (note 1) C15 multilayer ceramic chip capacitor 150 pF (note 1) L1 5 turns enamelled 0.7 mm copper 133 nH length 4.5 mm; wire int. dia. 6 mm; leads $2 \times 5$ mm L2, L3 stripline (note 2) 41.1 Ω length $13 \times 6$ mm L4 7 turns enamelled 1.5 mm copper 236 nH length 12.5 mm; wire int. dia. 8 mm; leads $2 \times 5$ mm grade 3B Ferroxcube wideband HF L5 4312 020 36642 choke L6 5 turns enamelled 2 mm copper 170 nH length 11.5 mm; wire int. dia. 8 mm; leads $2 \times 5$ mm R1, R2 1 W metal film resistor 10 Ω 0.4 W metal film resistor $10 \ k\Omega$ R2 R3 0.4 W metal film resistor 1 MΩ R5 1 W metal film resistor 10 kΩ

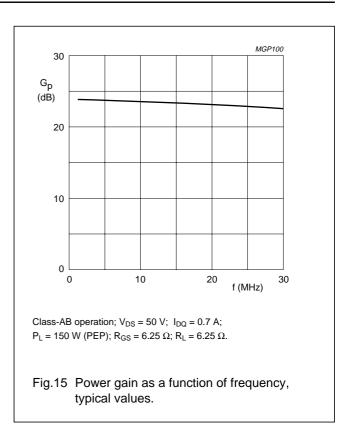
#### List of components (class-AB test circuit)

#### Notes

1. American Technical Ceramics (ATC) capacitor, type 100B or other capacitor of the same quality.

2. The striplines are on a double copper-clad printed circuit board, with PTFE fibre-glass dielectric ( $\epsilon_r$  = 2.2), thickness 1.6 mm.



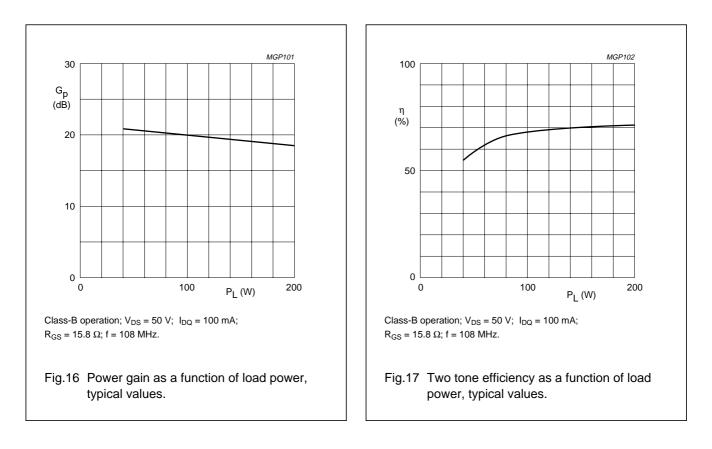


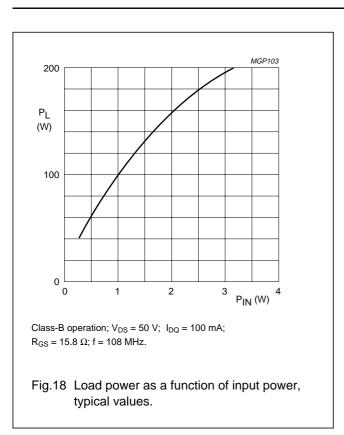
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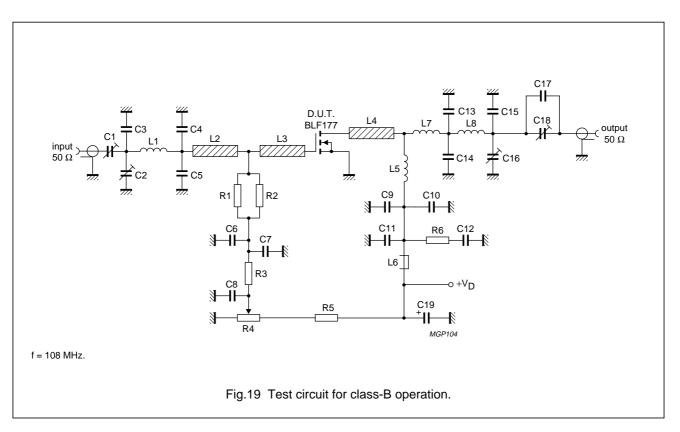
### APPLICATION INFORMATION FOR CLASS-B OPERATION

 $T_h = 25 \text{ °C}$ ;  $R_{th \text{ mb-h}} = 0.2 \text{ K/W}$ ;  $R_{GS} = 15.8 \Omega$ ; unless otherwise specified. RF performance in CW operation in a common source class-B test circuit.

MODE OF	f	V <sub>DS</sub>	І <sub>DQ</sub>	P <sub>L</sub>	G <sub>P</sub>	η <sub>D</sub>
OPERATION	(MHz)	(V)	(А)	(W)	(dB)	(%)
CW, class-B	108	50	0.1	150	typ. 19	typ. 70







BLF177

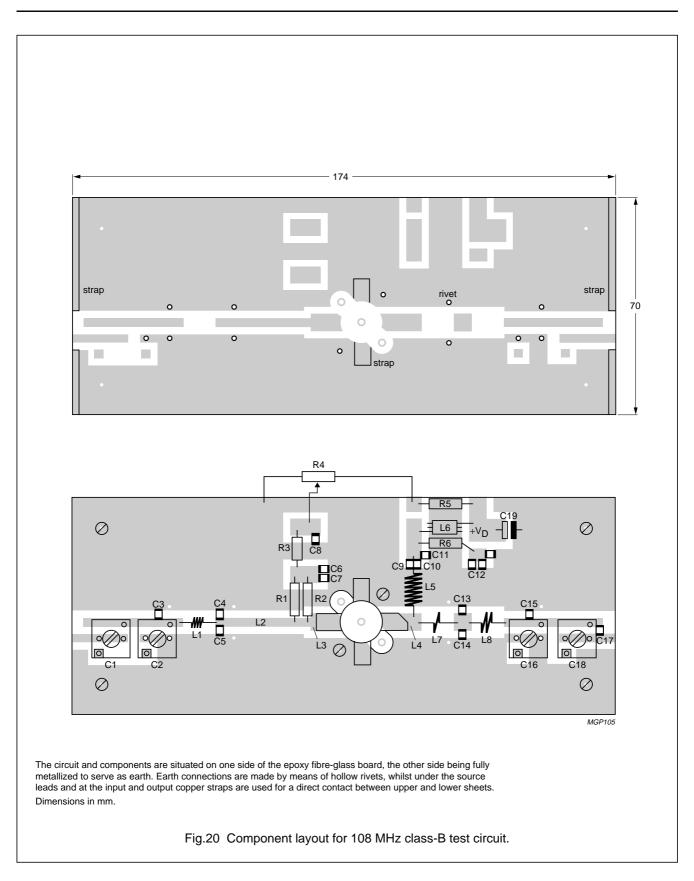
COMPONENT	DESCRIPTION	VALUE	DIMENSIONS	CATALOGUE NO.
C1, C2, C16, C18	film dielectric trimmer	2.5 to 20 pF		2222 809 07004
C3	multilayer ceramic chip capacitor (note 1)	20 pF		
C4, C5	multilayer ceramic chip capacitor (note 1)	62 pF		
C6, C7, C9, C10	multilayer ceramic chip capacitor (note 1)	1 nF		
C8	multilayer ceramic chip capacitor	100 nF		2222 852 47104
C11	multilayer ceramic chip capacitor	10 nF		2222 852 47103
C12	multilayer ceramic chip capacitor	3×100 nF		2222 852 47104
C13, C14	multilayer ceramic chip capacitor (note 1)	36 pF		
C15	multilayer ceramic chip capacitor (note 1)	12 pF		
C17	multilayer ceramic chip capacitor (note 1)	5.6 pF		
C19	electrolytic capacitor	4.4 μF, 63 V		2222 030 28478
L1	3 turns enamelled 0.8 mm copper wire	22 nH	length 5.5 mm; int. dia. 3 mm; leads $2 \times 5$ mm	
L2	stripline (note 2)	64.7 Ω	31 × 3 mm	
L3, L4	stripline (note 2)	41.1 Ω	10 × 6 mm	
L5	6 turns enamelled 1.6 mm copper wire	122 nH	length 13.8 mm; int. dia. 6 mm; leads $2 \times 5$ mm	
L6	grade 3B Ferroxcube wideband HF choke			4312 020 36642
L7	1 turn enamelled 1.6 mm copper wire	16.5 nH	int. dia. 9 mm; leads $2 \times 5$ mm	
L8	2 turns enamelled 1.6 mm copper wire	34.4 nH	length 3.9 mm; int. dia. 6 mm; leads 2 × 5 mm	
R1, R2	1 W metal film resistor	31.6 Ω		
R3	0.4 W metal film resistor	1 kΩ		
R4	cermet potentiometer	5 kΩ		
R5	0.4 W metal film resistor	44.2 Ω		
R6	1 W metal film resistor	10 Ω		

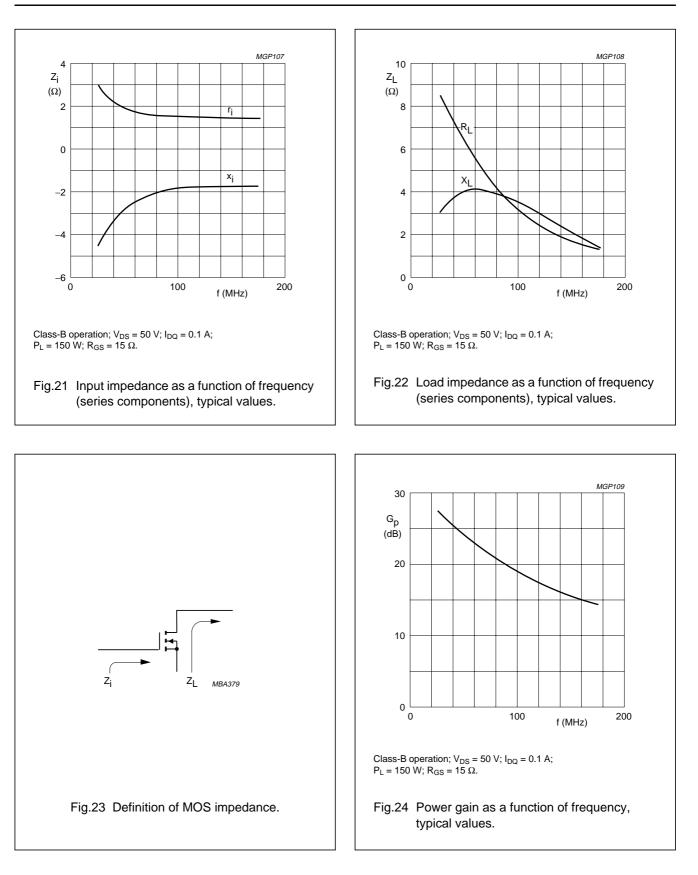
#### List of components (class-B test circuit)

### Notes

1. American Technical Ceramics (ATC) capacitor, type 100B or other capacitor of the same quality.

2. The striplines are on a double copper-clad printed circuit board, with PTFE fibre-glass dielectric ( $\epsilon_r$  = 2.2), thickness 1.6 mm.



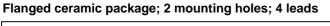


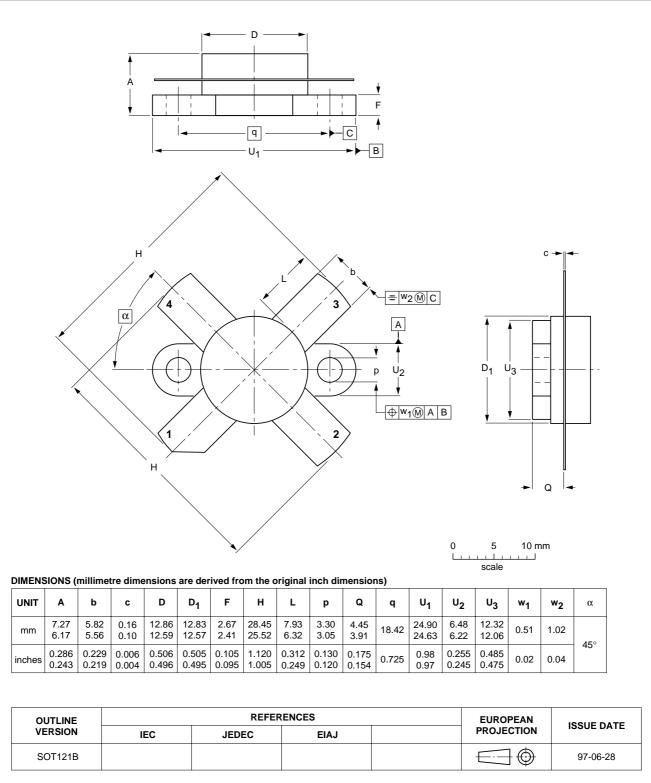
BLF177

### HF/VHF power MOS transistor

### PACKAGE OUTLINE

**Philips Semiconductors** 





SOT121B

### Product specification

### BLF177

#### DEFINITIONS

Data Sheet Status	
Objective specification	This data sheet contains target or goal specifications for product development.
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.
Product specification	This data sheet contains final product specifications.
Limiting values	
more of the limiting values n of the device at these or at a	accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or nay cause permanent damage to the device. These are stress ratings only and operation any other conditions above those given in the Characteristics sections of the specification imiting values for extended periods may affect device reliability.

### Application information

Where application information is given, it is advisory and does not form part of the specification.

#### LIFE SUPPORT APPLICATIONS

These products are not designed for use in life support appliances, devices, or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips for any damages resulting from such improper use or sale.